

FQP6N40CF / FQPF6N40CF N-Channel QFET FRFET MOSFET 400 V, 6.0 A, 1.1 Ω

March 2013

Description

This N-Channel enhancement mode power MOSFET is produced using Fairchild Semiconductor®'s proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state resistance, and to provide superior switching performance and high avalanche energy strength. These devices are suitable for switched mode power supplies, active power factor correction (PFC), and electronic lamp ballasts.

Features

- 6.0 A, 400 V, $R_{DS(on)}$ = 1.1 Ω (Max) $@V_{GS}$ = 10 V, I_D = 3.0 A
- Low Gate Charge (Typ. 16 nC)
- Low Crss (Typ. 15 pF)
- 100% Avalanche Tested



Absolute Maximum Ratings

Symbol	Parameter			FQP6N40CF	FQPF6N40CF	Unit
V _{DSS}	Drain-Source Voltage		400		V	
I _D	Drain Current	- Continuous (T _C = 25°C)		6	6*	Α
		- Continuous (T _C = 100°C	;)	3.6	3.6*	Α
I _{DM}	Drain Current	- Pulsed	(Note 1)	24	24*	Α
V _{GSS}	Gate-Source Voltage		± 30		V	
E _{AS}	Single Pulsed Avalanche Energy		(Note 2)	270		mJ
I _{AR}	Avalanche Current		(Note 1)	6		Α
E _{AR}	Repetitive Avalanche Energy		(Note 1)	73		mJ
dv/dt	Peak Diode Recovery dv/dt (Note		(Note 3)	20		V/ns
P _D	Power Dissipation (T _C = 25°C)		73	38	W	
	- Derate above 25°C		0.58	0.3	W/°C	
T _J , T _{STG}	Operating and Storage Temperature Range			-55 to +150		°C
T _L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300		°C	

^{*} Drain current limited by maximum junction temperature

Thermal Characteristics

Symbol	Parameter	FQP6N40CF	FQPF6N40CF	Unit
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	1.71	3.31	°C/W
$R_{\theta CS}$	Thermal Resistance, Case-to-Sink	0.5		°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	62.5	62.5	°C/W

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FQP6N40CF	FQP6N40CF	TO-220	-	-	50
FQPF6N40CF	FQPF6N40CF	TO-220F	-	-	50

Electrical Characteristics T_C = 25°C unless otherwise noted

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
Off Characte	ristics	•			•	•
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} = 0 V, I _D = 250 μA	400			V
ΔBV _{DSS} / ΔΤ _J	Breakdown Voltage Temperature Coefficient	I _D = 250 μA, Referenced to 25°C		0.54		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 400 V, V _{GS} = 0 V			1	μА
		V _{DS} = 320 V, T _C = 125°C			10	μА
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = 30 V, V _{DS} = 0 V			100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	V _{GS} = -30 V, V _{DS} = 0 V			-100	nA
On Characte	eristics					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2.0		4.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = 10 V, I _D = 3 A		0.9	1.1	Ω
g _{FS}	Forward Transconductance	V _{DS} = 40 V, I _D = 3 A (Note 4)		4.7		S
Dynamic Characteristics Constant Input Canacitance Vpg = 25 V Vgg = 0 V				480	625	pF
C _{iss}	Input Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz		480	625	pF
C _{oss}	Output Capacitance	- 1.0 WHZ		80	105	pF
C _{rss}	Reverse Transfer Capacitance			15	20	pF
Switching C	haracteristics					
t _{d(on)}	Turn-On Delay Time	V _{DD} = 200 V, I _D = 6 A,		13	35	ns
t _r	Turn-On Rise Time	$R_G = 25 \Omega$		65	140	ns
t _{d(off)}	Turn-Off Delay Time			21	55	ns
t _f	Turn-Off Fall Time	(Note 4, 5)		38	85	ns
Q _g	Total Gate Charge	V _{DS} = 320 V, I _D = 6 A,		16	20	nC
Q _{gs}	Gate-Source Charge	V _{GS} = 10 V		2.3		nC
Q _{gd}	Gate-Drain Charge	(Note 4, 5)		8.2		nC
Drain-Source	e Diode Characteristics and Maximum R	atings				
I _S	Maximum Continuous Drain-Source Diode Forward Current				6	Α
I _{SM}	Maximum Pulsed Drain-Source Diode Forward Current				24	Α
V _{SD}	Drain-Source Diode Forward Voltage	V _{GS} = 0 V, I _S = 6 A			1.4	V
t _{rr}	Reverse Recovery Time	V _{GS} = 0 V, I _S = 6 A,		70		ns
Q _{rr}	Reverse Recovery Charge	$dI_F / dt = 100 A/\mu s$ (Note 4)		0.12		μС

Notes:

- ${\bf 1.} \ {\bf Repetitive} \ {\bf Rating}: {\bf Pulse} \ {\bf width} \ {\bf limited} \ {\bf by} \ {\bf maximum} \ {\bf junction} \ {\bf temperature}$
- 2. L = 13.7mH, I $_{AS}$ = 6A, V $_{DD}$ = 50V, R $_{G}$ = 25 Ω , Starting T $_{J}$ = 25°C
- 3. $I_{SD} \le 6A$, di/dt $\le 200A/\mu s$, $V_{DD} \le BV_{DSS}$, Starting T_J = 25°C
- 4. Pulse Test : Pulse width $\leq 300 \mu s,$ Duty cycle $\leq 2\%$
- 5. Essentially independent of operating temperature

Typical Performance Characteristics

Figure 1. On-Region Characteristics

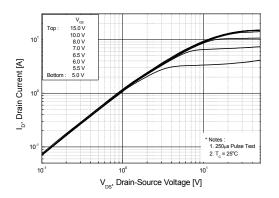


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

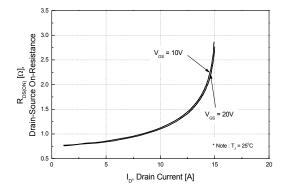


Figure 5. Capacitance Characteristics

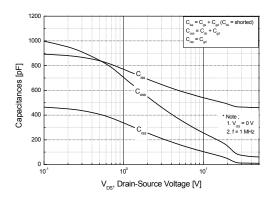


Figure 2. Transfer Characteristics

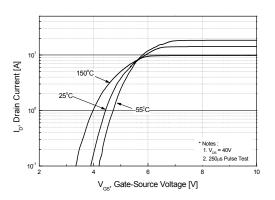


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperatue

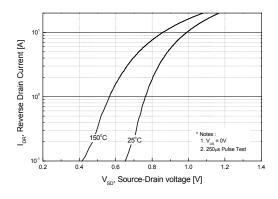
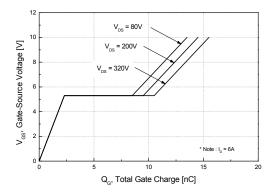


Figure 6. Gate Charge Characteristics



Typical Performance Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

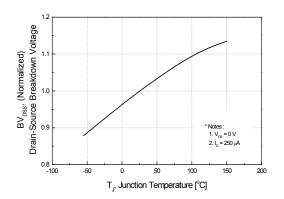


Figure 8. On-Resistance Variation vs. Temperature

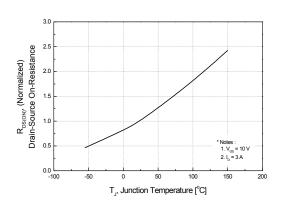


Figure 9-1. Maximum Safe Operating Area for FQP6N40CF

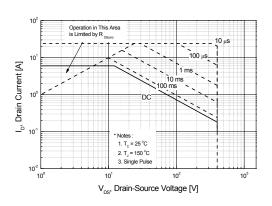


Figure 9-2. Maximum Safe Operating Area for FQPF6N40CF

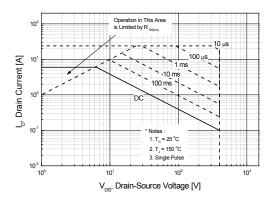
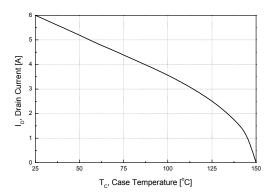


Figure 10. Maximum Drain Current vs. Case Temperature



Typical Performance Characteristics (Continued)

Figure 11-1. ransient Thermal Response Curve for FQP6N40CF

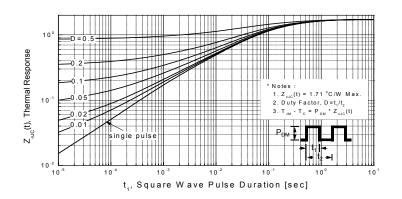
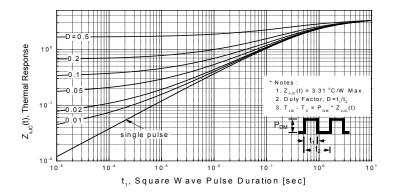
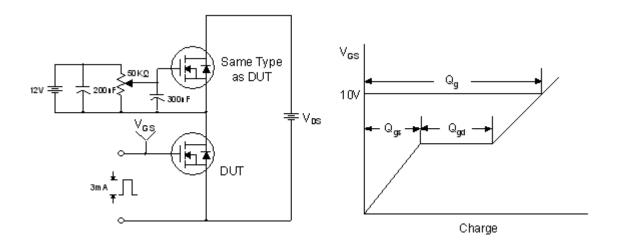


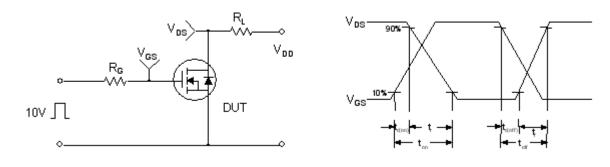
Figure 11-2. Transient Thermal Response Curve for FQPF6N40CF



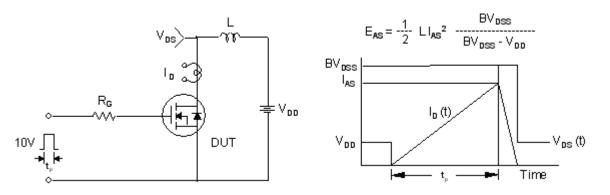
Gate Charge Test Circuit & Waveform



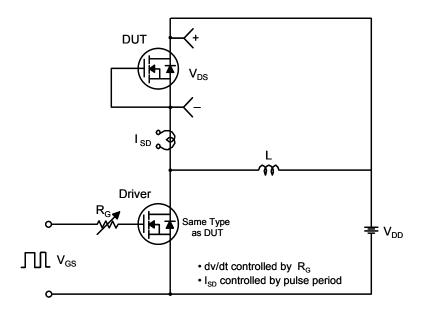
Resistive Switching Test Circuit & Waveforms

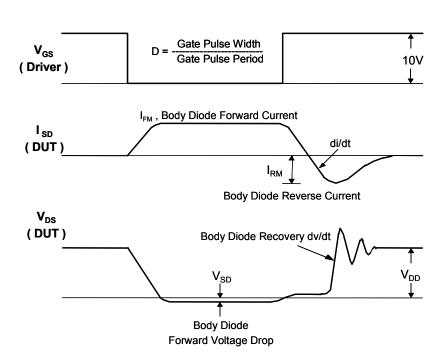


Unclamped Inductive Switching Test Circuit & Waveforms



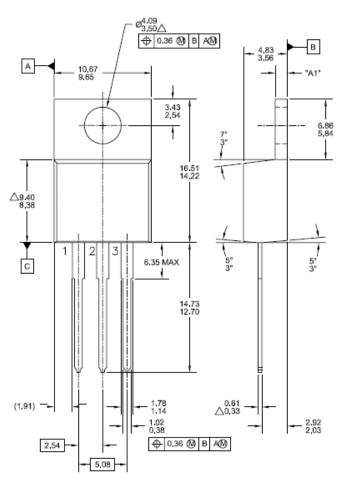
Peak Diode Recovery dv/dt Test Circuit & Waveforms

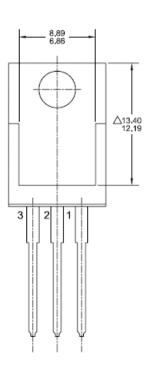


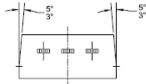


Mechanical Dimensions

TO-220



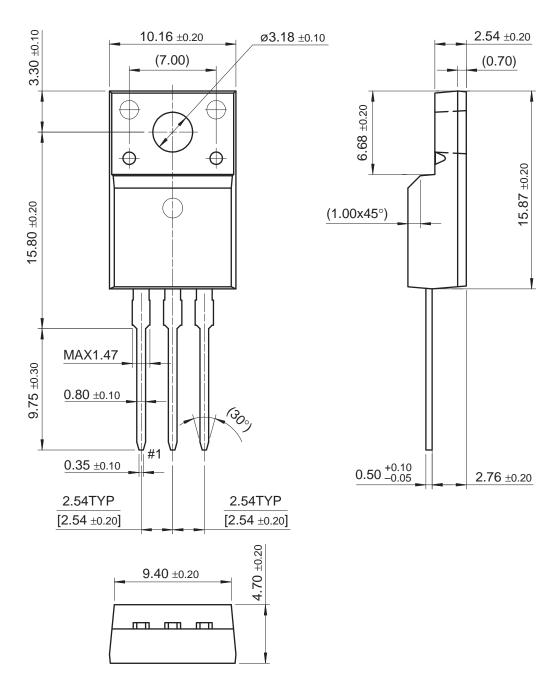




Dimensions in Millimeters

Mechanical Dimensions (Continued)

TO-220F



Dimensions in Millimeters





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